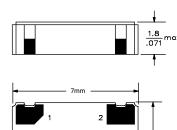


3.3V CMOS Low Jitter, High Frequency **Crystal Clock Oscillator (XO)**

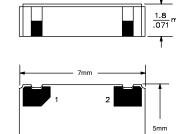




Packaging Outline



Pin Functions		
Pin	Function	
1	OE Function	
2	Ground	
3	Clock Output	
4	VDD	

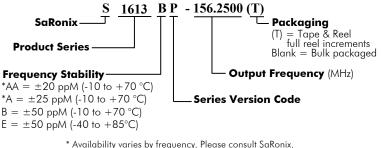


Common Frequencies

Contact SaRonix for additional frequencies

100.0000 MHz	150.0000 MHz
106.2500 MHz	155.5200 MHz
125.0000 MHz	156.2500 MHz
127.0000 MHz	159.3750 MHz
133.0000 MHz	

Ordering Information



Actual Size $= 5 \times 7$ mm



Product Features

- Thicker crystal for improved reliability
- Less than 1 ps RMS jitter with advanced non-PLL, patent-pending design
- \pm 50ppM accuracy (all rated conditions including aging) standard for commercial or industrial operating conditions
- 3.3V CMOS/TTL compatible logic levels
- Pin-compatible with standard 5x7mm packages
- Designed for standard reflow and washing techniques
- IBIS model available •
- Pb-free and RoHS/Green compliant** ٠ (**per #7, Annex of Directive 2002/05/EC)

Product Description

The S1613XP Series is an enhanced high-frequency version of the popular \$1613 series, a 3.3V crystal clock oscillator that achieves superb jitter and stability over a broad range of operating conditions and frequencies. The output clock signal, generated internally with a non-PLL oscillator design, is compatible with LVCMOS/LVTTL logic levels. The device, available on tape and reel, is contained in a 5x7mm surface-mount ceramic package.

Applications

The S1613XP Series is an ideal reference clock for highspeed applications requiring low jitter, including:

- 1/10 Gigabit Ethernet
- FibreChannel •
- Serial Attached SCSI (SAS)
- Server & Storage platforms
- SONET/SDH linecards





3.3V CMOS Low Jitter, High Frequency Crystal Clock Oscillator (XO)

Electrical Performance

Parameter	Min.	Тур.	Max.	Units	Notes
Output frequency	100		160	MHz	As specified
Supply voltage	+2.97	+3.3	+3.63	V	
Supply current, output enabled			30	mA	
Supply current, output disabled			10	mA	Output Hi-Z
Frequency stability			±20 to ±50	ррМ	See Note 1 below
Operating temperature	-40		+85	°C	As specified
Output logic 0, VOL			10% V _{DD}	V	
Output logic 1, VOH	90% V _{DD}			V	
Output load	15 pF (max) or 10 LSTTL			TL	
Duty cycle	45		55	%	-10 to +70°C measured 50%VDD
Duty cycle	40		60	%	-40 to -10°C, +70 to +85°C measured 50%VDD
Rise and fall time			2	ns	measured 20/80% of waveform
Jitter, phase		0.25	1	ps RMS (1-σ)	12kHz to 40MHz frequency band
Jitter, accumulated			7	ps RMS (1-σ)	20,000 adjacent periods
Jitter, total			40	ps pk-pk	100,000 random periods
Subharmonic Level			-40	dBc	

Notes:

1. As specified. Stability includes all combinations of operating temperature, load changes, rated input (supply) voltage changes, initial calibration tolerance (25°C), aging (1 year at 25°C average effective ambient temperature), shock and vibration.

Sulput Enable / Disable Function					
Parameter	Min.	Тур.	Max.	Units	Notes
Input Voltage (pin 1), Output Enable	2.2			V	or open
Input voltage (pin 1), Output Disable			0.8	V	Output is Hi-Z
Internal pullup resistance	50			kΩ	
Output disable delay			100	ns	
Output enable delay			1	ms	

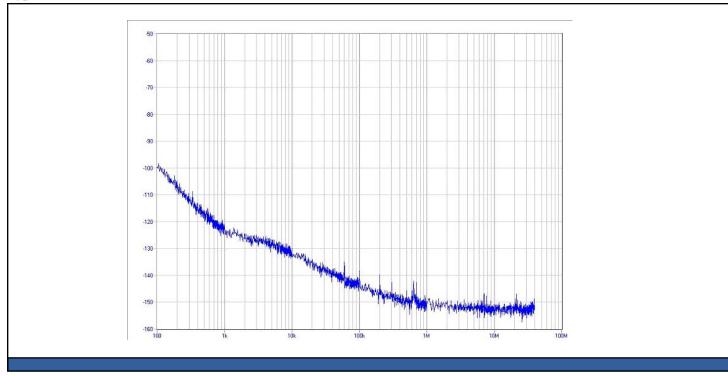
Output Enable / Disable Function



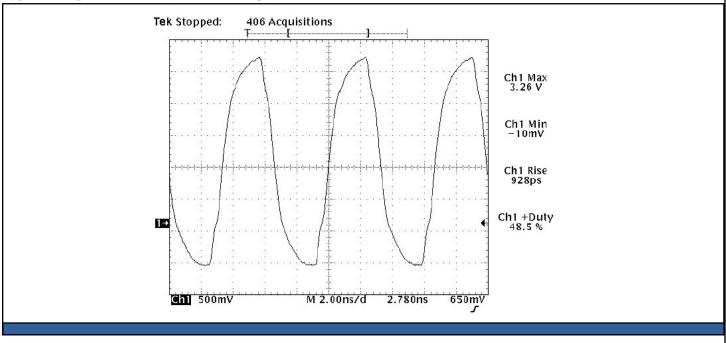


3.3V CMOS Low Jitter, High Frequency Crystal Clock Oscillator (XO)

Typical Phase Noise



Typical Output Waveform (150 MHz output)



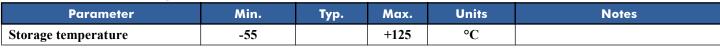
All specifications are subject to change without notice. DS 263 Rev B | 08/19/05



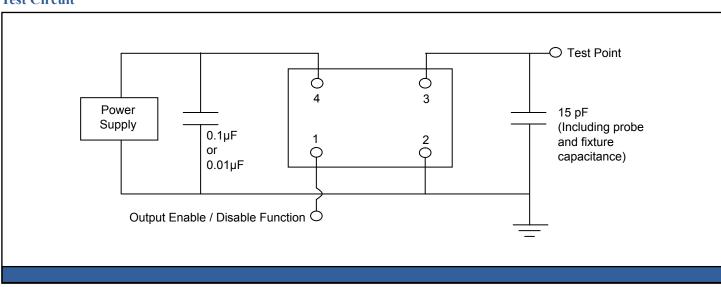


3.3V CMOS Low Jitter, High Frequency Crystal Clock Oscillator (XO)

Absolute Maximum Ratings



Test Circuit



Reliability Test Ratings

This product is rated to meet the following test conditions:

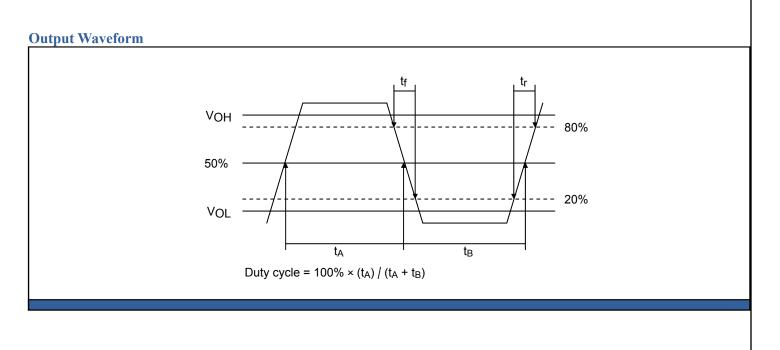
Туре	Parameter	Test Condition
Mechanical	Shock	MIL-STD-883, Method 2002, Condition B
Mechanical	Solderability	JESD22-B102-D Method 2 (Preconditioning E)
Mechanical	Terminal strength	MIL-STD-883, Method 2004, Condition D
Mechanical	Gross leak	MIL-STD-883, Method 1014, Condition C
Mechanical	Fine leak	MIL-STD-883, Method 1014, Condition A2 ($R_1 = 2x10^{-8}$ atm cc/s)
Mechanical	Solvent resistance	MIL-STD-202, Method 215
Environmental	Thermal shock	MIL-STD-883, Method 1011, Condition A
Environmental	Moisture resistance	MIL-STD-883, Method 1004
Environmental	Vibration	MIL-STD-883, Method 2007, Condition A
Environmental	Resistance to soldering heat	J-STD-020C Table 5-2 Pb-free devices (2 cycles max)



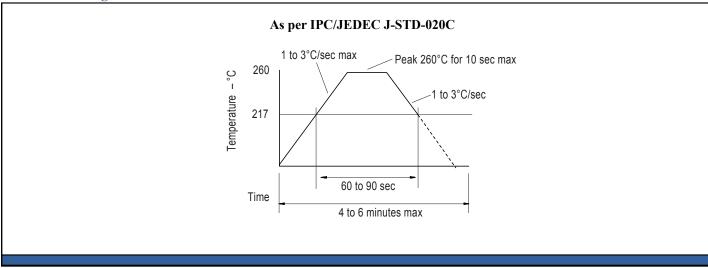
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3.3V CMOS Low Jitter, High Frequency Crystal Clock Oscillator (XO)



Reflow Soldering Profile



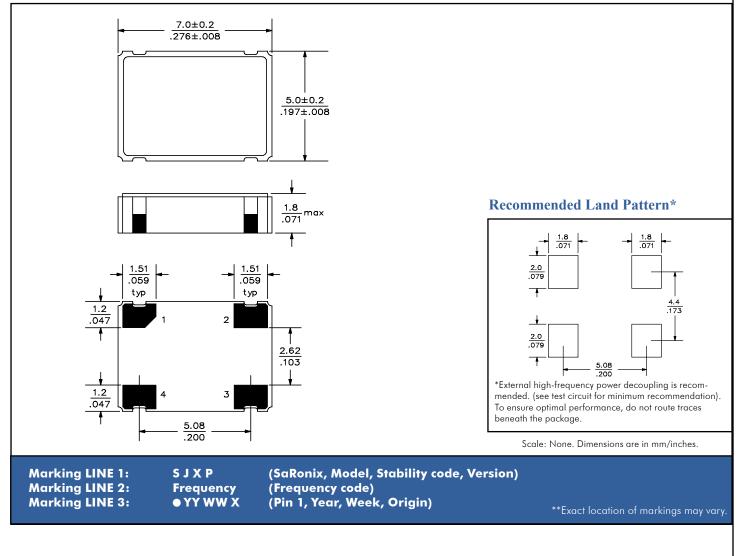
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3.3V CMOS Low Jitter, High Frequency Crystal Clock Oscillator (XO)

Mechanical Drawings



All specifications are subject to change without notice. DS 263 Rev B | 08/19/05

